

Notice of References Cited	Application/Control No. 09/801,200		Applicant(s)/Patent Under Reexamination SHIMAZAKI ET AL.	
	Examiner Shambhavi Patel		Art Unit 2128	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,035,048	03-2000	Diethorn, Eric John	381/94.3
	B	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Hayashi et al. 'EMI-Noise Analysis under ASIC Design Environment'. ACM Press, 1999; pages 16-21
	V	Cheng et al. 'Power Supply Noise Analysis Methodology for Deep-Submicron VLSI Chip Design.' ACM 1997.
	W	'Engineer to Engineer Note' Analog Devices 1996.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.